

### FDR856P

## P-Channel Logic Level Enhancement Mode Field Effect Transistor

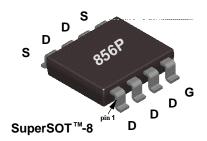
### **General Description**

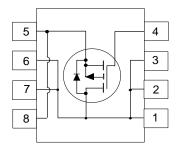
SuperSOT<sup>™</sup>-8 P-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance and provide superior switching performance. These devices are particularly suited for low voltage applications such as battery powered circuits or portable electronics where low in-line power loss, fast switching and resistance to transients are needed.

### **Features**

- = -6.3 A, -30 V, R  $_{\rm DS(ON)}$  =0.025  $\Omega$  @ V  $_{\rm GS}$  = -10 V  $R _{\rm DS(ON)}$  =0.040  $\Omega$  @ V  $_{\rm GS}$  = -4.5 V.
- SuperSOT<sup>TM</sup>-8 package: small footprint (40% less than SO-8);low profile (1mm thick);maximum power comperable to SO-8.
- High density cell design for extremely low R<sub>DS(ON)</sub>.





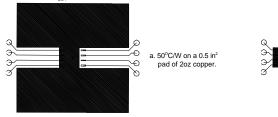


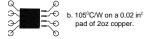
## **Absolute Maximum Ratings** $T_A = 25^{\circ}C$ unless other wise noted

Symbol	Parameter		FDR856P	Units		
V <sub>DSS</sub>	Drain-Source Voltage		-30			
V <sub>GSS</sub>	Gate-Source Voltage - Continuous		±20	V		
D	Maximum Drain Current - Continuo	US (Note 1a)	-5.1	А		
	- Pulseo	1	-50			
P <sub>D</sub>	Maximum Power Dissipation	(Note 1a)	1.8	W		
		(Note 1b)	1			
		(Note 1c)	0.9			
$T_{J}$ , $T_{STG}$	Operating and Storage Temperature	e Range	-55 to 150	°C		
ГНЕRMA	L CHARACTERISTICS	<u>.</u>		<u>.</u>		
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ar	mbient (Note 1a)	50	°C/W		
R <sub>euc</sub>	Thermal Resistance, Junction-to-Ca	ase (Note 1)	25	°C/W		

Symbol	Parameter	Conditions			Тур	Max	Units
OFF CHAF	RACTERISTICS					•	•
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$		-30			V
$\Delta$ BV <sub>DSS</sub> / $\Delta$ T <sub>J</sub>	Breakdown Voltage Temp. Coefficient	$I_D = -250 \mu\text{A}$ , Referenced	to 25 °C		-15		mV /°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = -24 \text{ V}, \ V_{GS} = 0 \text{ V}$				-1	μΑ
			T <sub>J</sub> = 55°C			-10	μA
I <sub>GSSF</sub>	Gate - Body Leakage, Forward	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
I <sub>GSSR</sub>	Gate - Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
ON CHARA	ACTERISTICS (Note 2)						
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$		-1	-1.5	-3	V
$\Delta V_{GS(th)}/\Delta T_{J}$	Gate Threshold Voltage Temp. Coefficient	I <sub>D</sub> = -250 μA, Referenced	to 25 °C		3		mV /°C
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	$V_{GS} = -10 \text{ V}, I_{D} = -6.3 \text{ A}$			0.022	0.025	Ω
,			T <sub>J</sub> =125°C		0.03	0.042	1
		$V_{GS} = -4.5 \text{ V}, I_{D} = -5 \text{ A}$			0.033	0.04	1
I <sub>D(ON)</sub>	On-State Drain Current	$V_{GS} = -10 \text{ V}, \ V_{DS} = -5 \text{ V}$		-50			Α
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = -10 \text{ V}, I_{D} = -6.3 \text{ A}$			15		S
DYNAMIC	CHARACTERISTICS	-				•	•
C <sub>iss</sub>	Input Capacitance	$V_{DS} = -15 \text{ V}, \ V_{GS} = 0 \text{ V},$			1370		pF
C <sub>oss</sub>	Output Capacitance	f = 1.0 MHz			740		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			220		pF	
SWITCHIN	G CHARACTERISTICS (Note 2)						
t <sub>D(on)</sub>	Tum - On Delay Time	$V_{DS} = -15 \text{ V}, I_{D} = -1 \text{ A}$			7	14	ns
t <sub>r</sub>	Turn - On Rise Time	$V_{GS} = -10 \text{ V}$ , $R_G = 6 \Omega$			12	19	ns
t <sub>D(off)</sub>	Turn - Off Delay Time				80	100	ns
t,	Turn - Off Fall Time				130	160	ns
$Q_g$	Total Gate Charge	$V_{DS} = -15 \text{ V}, I_{D} = -6.3 \text{ A},$			22	31	nC
$Q_{gs}$	Gate-Source Charge	V <sub>GS</sub> = -10 V			3.8		nC
$Q_{gd}$	Gate-Drain Charge				8.7		nC
DRAIN-SO	URCE DIODE CHARACTERISTICS AND MAX	IMUM RATINGS					
l <sub>s</sub>	Maximum Continuous Drain-Source Diode For	rward Current				-1.3	Α
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	_	-0.73	-1.2	V		

1. R<sub>Bux</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R<sub>Bux</sub> is guaranteed by design while R<sub>Bux</sub> is determined by the user's board design.







Scale 1 : 1 on letter size paper 2. Pulse Test: Pulse Width  $\leq$  300 $\mu$ s, Duty Cycle  $\leq$  2.0%.

### **Typical Electrical Characteristics**

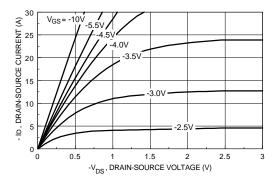


Figure 1. On-Region Characteristics.

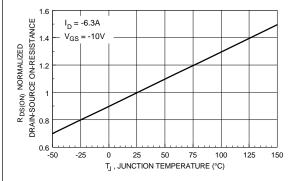


Figure 3. On-Resistance Variation with Temperature.

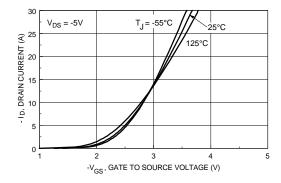


Figure 5 . Transfer Characteristics.

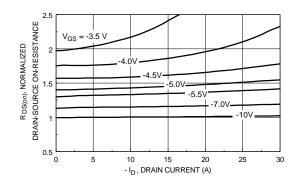


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

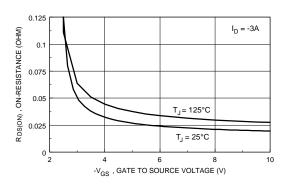


Figure 4 . On Resistance Variation with Gate-to-Source Voltage.

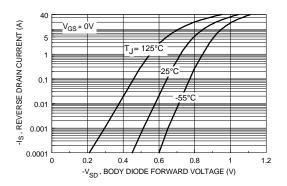


Figure 6 . Body Diode Forward Voltage Variation with Source Current and Temperature.

## Typical Electrical Characteristics (continued)

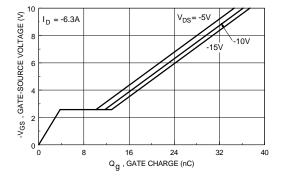


Figure 7. Gate Charge Characteristics.

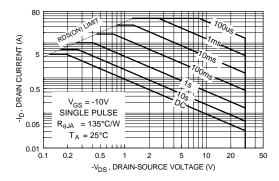


Figure 9. Maximum Safe Operating Area.

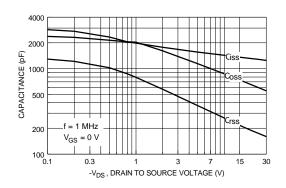


Figure 8. Capacitance Characteristics.

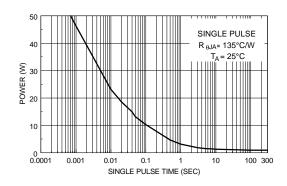


Figure 10. Single Pulse Maximum Power Dissipation.

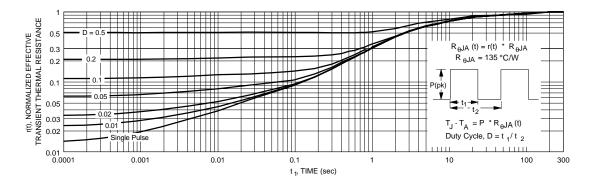
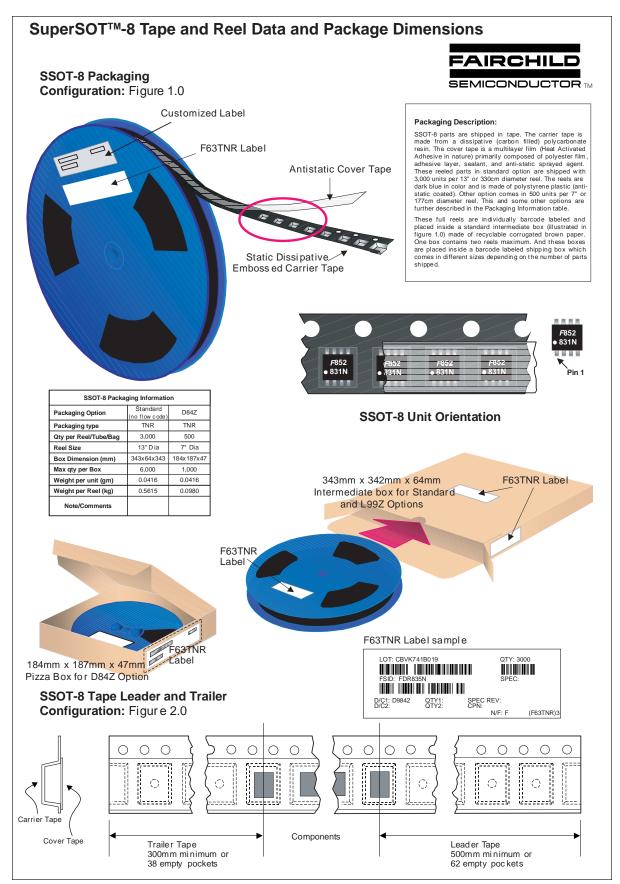
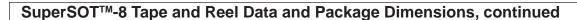


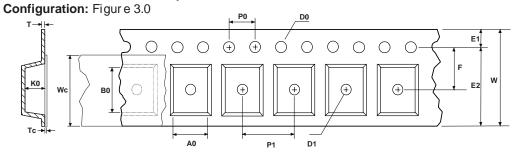
Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.





## **SSOT-8 Embossed Carrier Tape**



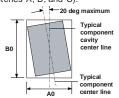


Dimensions are in millimeter														
Pkg type	A0	В0	w	D0	D1	E1	E2	F	P1	P0	K0	Т	Wc	Тс
<b>SSOT-8</b> (12mm)	4.47 +/-0.10	5.00 +/-0.10	12.0 +/-0.3	1.55 +/-0.05	1.50 +/-0.10	1.75 +/-0.10	10.25 min	5.50 +/-0.05	8.0 +/-0.1	4.0 +/-0.1	1.37 +/-0.10	0.280 +/-0.150	9.5 +/-0.025	0.06 +/-0.02

Notes: A0, B0, and K0 dimensions are determined with respect to the EIA/Jedec RS-481 rotational and lateral movement requirements (see sketches A, B, and C).



Sketch A (Side or Front Sectional View)
Component Rotation

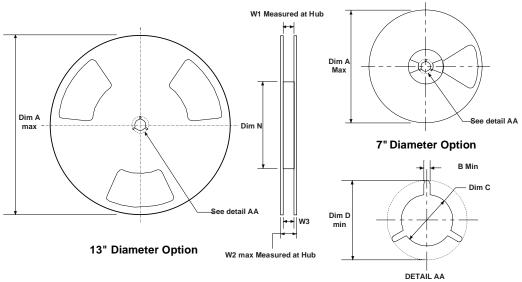


Sketch B (Top View)
Component Rotation



Sketch C (Top View)
Component lateral movement

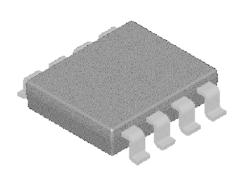
# SSOT-8 Reel Configuration: Figur e 4.0

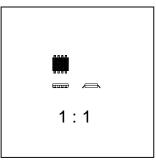


Dimensions are in inches and millimeters									
Tape Size	Reel Option	Dim A	Dim B	Dim C	Dim D	Dim N	Dim W1	Dim W2	Dim W3 (LSL-USL)
12mm	7" Dia	7.00 177.8	0.059 1.5	512 +0.020/-0.008 13 +0.5/-0.2	0.795 20.2	5.906 150	0.488 +0.078/-0.000 12.4 +2/0	0.724 18.4	0.469 - 0.606 11.9 - 15.4
12mm	13" Dia	13.00 330	0.059 1.5	512 +0.020/-0.008 13 +0.5/-0.2	0.795 20.2	7.00 178	0.488 +0.078/-0.000 12.4 +2/0	0.724 18.4	0.469 - 0.606 11.9 - 15.4

## SuperSOT™-8 Tape and Reel Data and Package Dimensions, continued

## SuperSOT™-8 (FS PKG Code 34, 35)

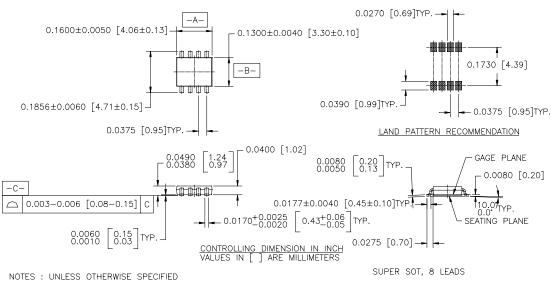




Scale 1:1 on letter size paper

Dimensions shown below are in: inches [millimeters]

Part Weight per unit (gram): 0.0416



STANDARD LEAD FINISH TI BE 200 MICROINCHES / 5.08 MICROMETERS MINIMUM TIN/LEAD (SOLDER) ON COPPER.

2. NO JEDEC REGISTRATION AS JAN. 1996

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